

| No. | Apparatus | Type | Price/hour Tax included | Operation Fee Tax included | |
|------|---|--|----------------------------|----------------------------------|-----------------------------|
| 1-1 | X-ray photoelectron spectrometer | ESCA-5800, Ulvac-Phi Inc. | 2200 | 24000/ sample | |
| 2-1 | X-ray photoelectron spectrometer | AXIS-ULTRA, Shimazu Corp. | 2700 | 5800/1H | |
| 3-1 | Secondary ion mass spectrometer | Atomika SIMS-4000, Analysetechnik GmbH | 1500 | 3900/1H | |
| 4-1 | Surface interface molecular vibration analysis system | Spectra-Physics, Tokyo Instruments Inc. | 1400 | 4500/1H | |
| 5-1 | Laser Raman Microscope system | Raman-touch, Nanophoton Corp. | 2000 | 4900/1H | |
| 5-3 | Micro-Raman RXN system | RAMAN RXN Systems, Kaiser Optical Systems, Inc. | 1600 | 4600/1H | |
| 6-1 | Laser Raman spectrometer | NRS-3100KK, JASCO Corp. | 2300 | 4900/1H | |
| 7-1 | UV-Vis-NIR spectrometer | SolidSpec-3700DUV, Shimazu Corp. | 600 | 3600/1H | |
| 7-2 | Fourier-transform infrared spectrometer | Spotlight 400, PerkinElmer Co., Ltd | 670 | 3800/1H | |
| 8-1 | UV-Vis-NIR spectrometer | V-670, JASCO Corp. | 1500 | 4400/1H | |
| 9-1 | High performance liquid chromatography | NexeraX2 (Shimazu Corp.), MicroOTOF-QIII (Bruker Corp.), J-1500 (JASCO Corp.), DLS-8000DL (Otsuka Electronics Co., Ltd.) | 1900 | 4800/1H | |
| 10-1 | Fluorolog-NIR spectrofluorometer | SPEX Fluorolog-NIR spectrophotometer, Horiba Ltd. | 1500 | 4100/1H | |
| 11-1 | Spectrofluorometer | NanoLog FL-322, Horiba Ltd. | 1000 | 4000/1H | |
| 13-1 | Nuclear magnetic resonance spectrometer | Avance 500MHz, Bruker Corp. | 940 | 1500/sample | |
| 14-1 | Time-of-flight mass spectrometer | JMS-T100CS, JEOL Ltd. | 680 | 2700/1H | |
| 15-1 | MALDI-TOF mass spectrometer | Autoflex III, Bruker Corp. | 1700 | 4500/1H | |
| 15-2 | Ultracentrifuge | CS100GXL, Hitachi Koki Co., Ltd. | 330 | 3300/1H | |
| 15-3 | High performance liquid chromatography | LC-908-C60, Japan Analytical Industry Co., Ltd. | 4200 | 7200/1H | |
| 16-1 | Scanning Probe Microscope | PicoPlus 5500, Agilent Technologies | 570 | 3200/1H | |
| 16-2 | Resistivity meter | Loresta-GP, Mitsubishi Chemical Corp. | 830 | 3800/1H | |
| 16-3 | Surface profiler | Dektak 6M, Veeco Instruments Inc. | 750 | 3200/1H | |
| 17-1 | Scanning Probe Microscope | SPM9600, Shimazu Corp. | 1200 | 4100/1H | |
| 17-2 | Scanning Probe Microscope | NanoscopeIIIa, Veeco Instruments Inc. | 2500 | 5400/1H | |
| 19-1 | Atomic force microscope | SPI3800N, Seiko Instruments Industry, Co., Ltd. | 380 | 3500/1H | |
| 20-1 | Cold field emission scanning electron microscope | SU9000, Hitachi High-Technologies Corp. | 1500 | 4500/1H | |
| 20-2 | 3D-SEM system | VE-9800, KEYENCE Corp. | 1100 | 4000/1H | |
| 21-1 | Scanning Electron Microscope | S-5000, Hitachi Corp. | 1900 | 4500/1H | |
| 22-1 | Transmission Electron Microscope | JEM-2010, JEOL, Ltd. | 880 | 3800/1H | |
| 22-2 | Atmospheric Scanning Electron microscope | JASM-6200, JEOL, Ltd. | 2900 | 6000/1H | |
| 23-1 | Zeta-potential and particle analyzer | ELS-Z, Otsuka Electronics Co., Ltd. | 1100 | 4100/1H | |
| 24-1 | Zeta-potential and particle analyzer | Nano ZS, Malvern Instruments | 2200 | 6200/1H | |
| 25-1 | Particle Sizer and Zeta Potential Analyzer | Zetasizer Nano ZS, Malvern Instruments | 960 | 4000/1H | |
| 26-1 | Intelligent X-ray diffraction (XRD) system | SmartLab, Rigaku Corp. | 2300 | 5200/1H | |
| 27-1 | Single crystal X-ray structure analysis apparatus | SMART APEX, Bruker Corp. | 3200 | 36000/sample | |
| 28-1 | Micro calorimeter | VP-ITC, Microcal Inc. | 2500 | 5400 | |
| 28-2 | Vapor pressure osmometer | OSMOMAT 070, Gonotec | 260 | 2900/1H | |
| 28-3 | Vapor pressure osmometer | Vapor Pressure Osmometer K-7000, Knauer | 260 | 3400/1H | |
| 29-1 | Molecular structure analysis system | | 320 | 3300/1H | |
| 30-1 | Fuel cell evaluation systems | AutoPEM-ER01, 02, Toyo Corp.; Hotpress SA-501, Tester Sangyo Co., Ltd. | 340 | 3400/1H | H ₂ cost 330/1 L |
| 30-2 | Catalyst activity/surface area measurement system | BELSORP-mini II, BELCAT-B, MicrotracBel Corp. | 390 | 3500/1H | |
| 31-1 | Solar cell characterization system | SRO-25GD, Bunkoukeiki Co.,Ltd | 4300 | 8200/1H | |